

Measuring Infrared Reflectivity of 3D Microantennas

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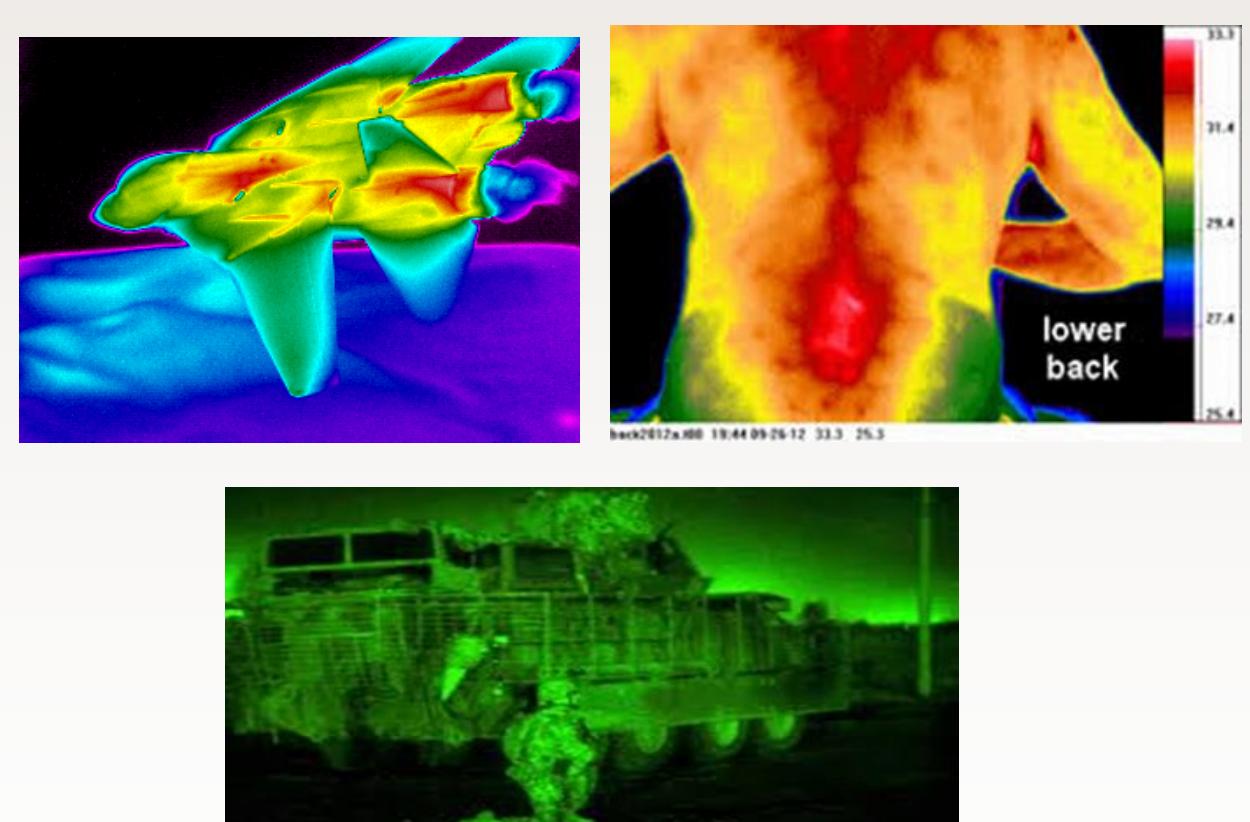
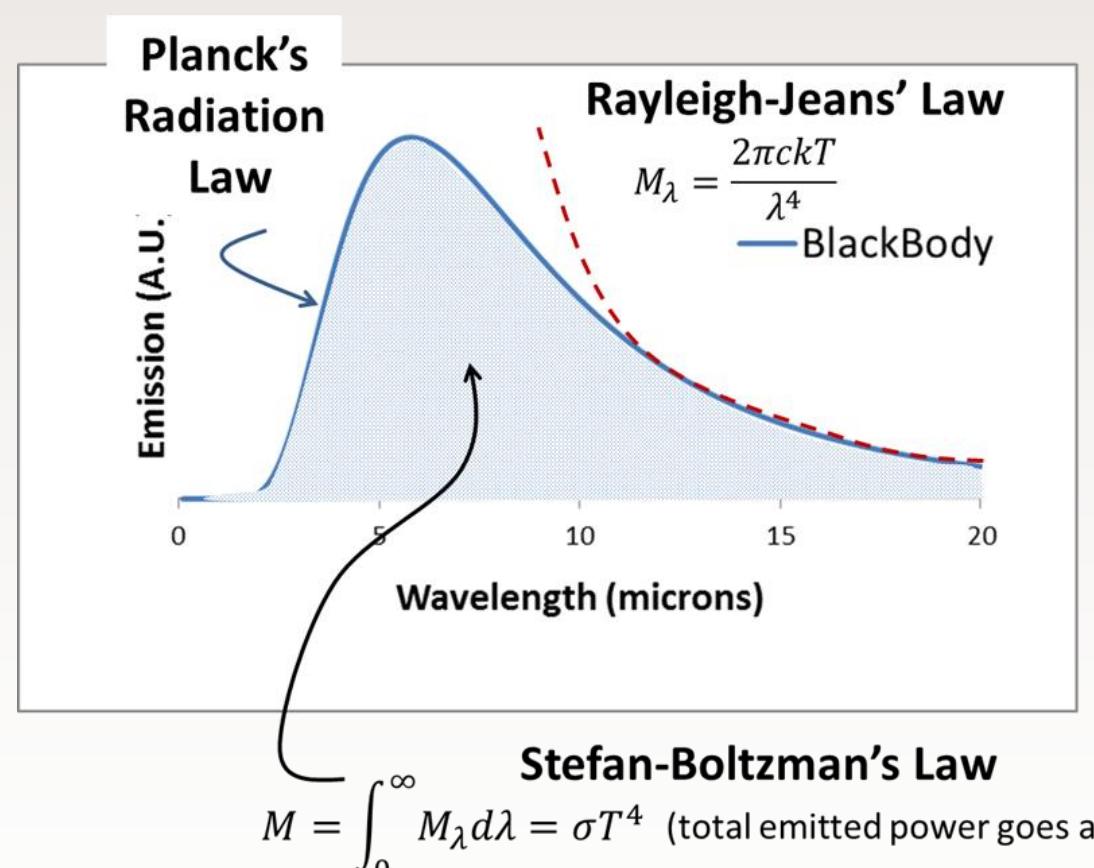
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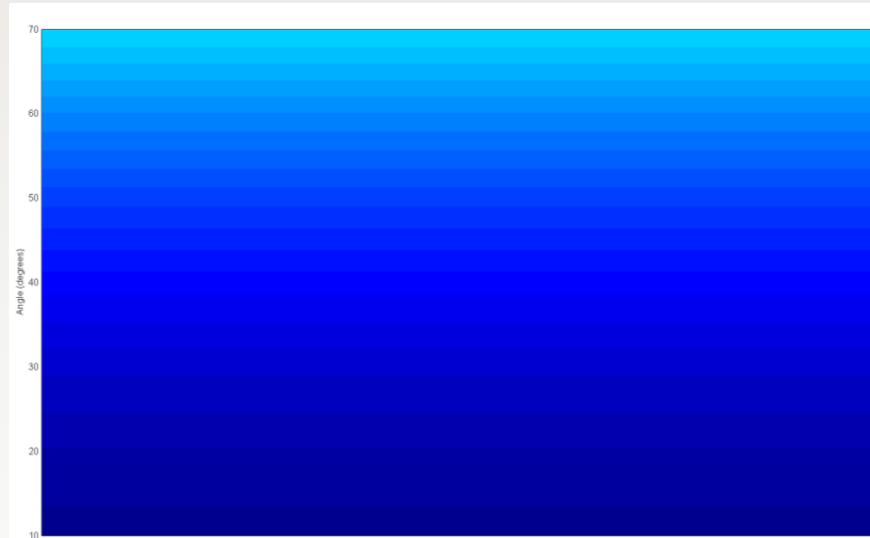
31 July, 2014

Objective: Understand the optical properties of 3D microstructures to be used in infrared applications

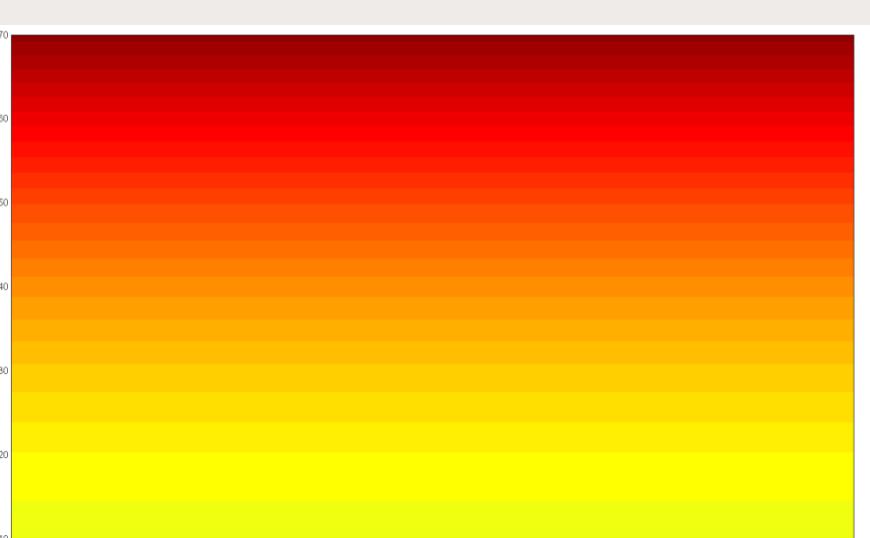
Background: All bodies emit thermal (IR) radiation according to Planck's law:



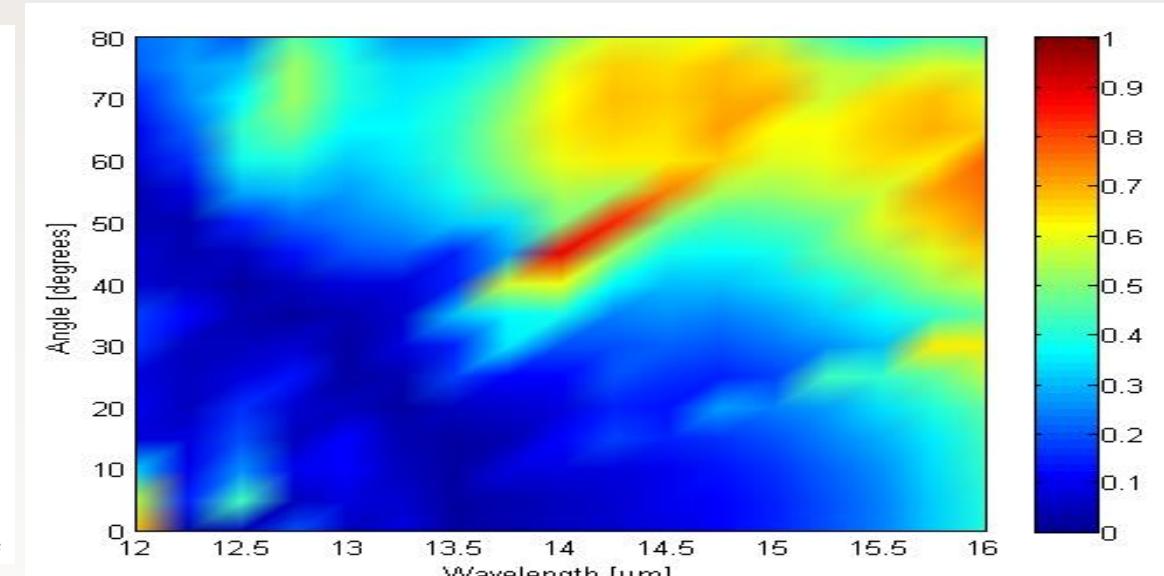
Example Reflection map for an unstructured absorptive Surface



Example Reflection map for an unstructured reflective Surface



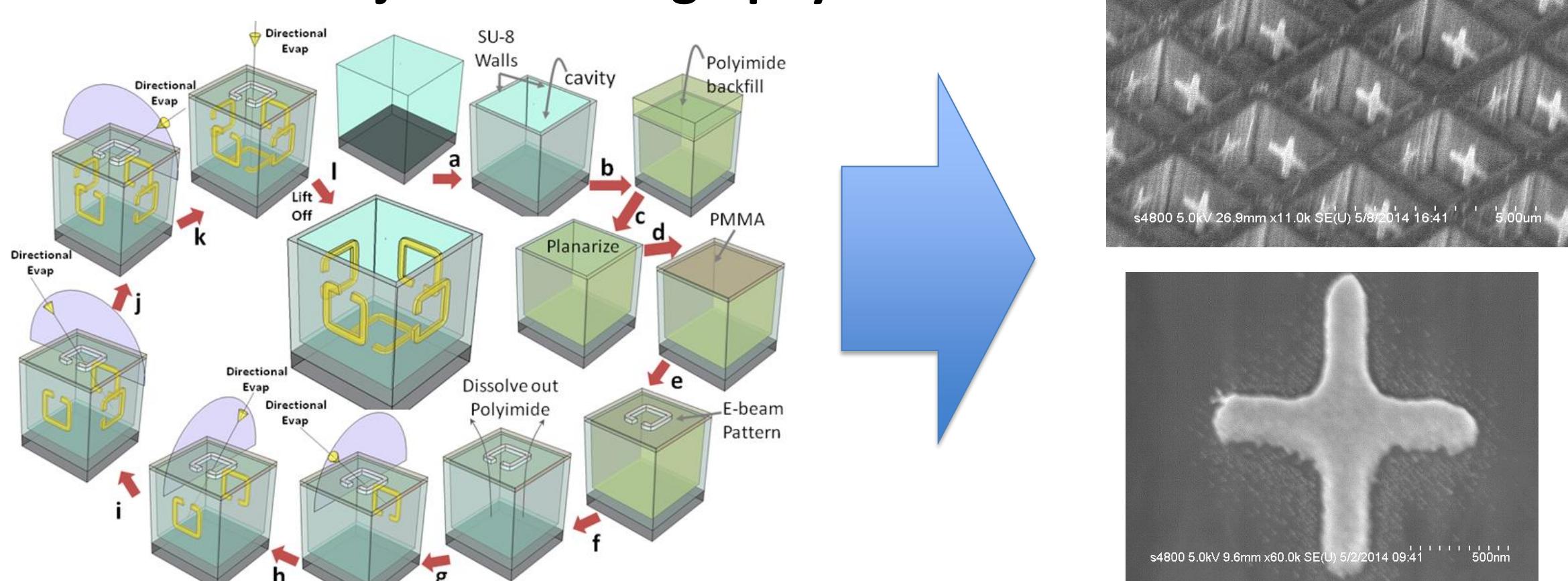
Example Reflection map for A structured electromagnetic material created with MPL



Measured Reflectance Data of Structured Electromagnetic Surfaces Generated with MPL

Applications which leverage IR radiation find use in night vision and other military technology, medical diagnostics, and more

Membrane Projection Lithography



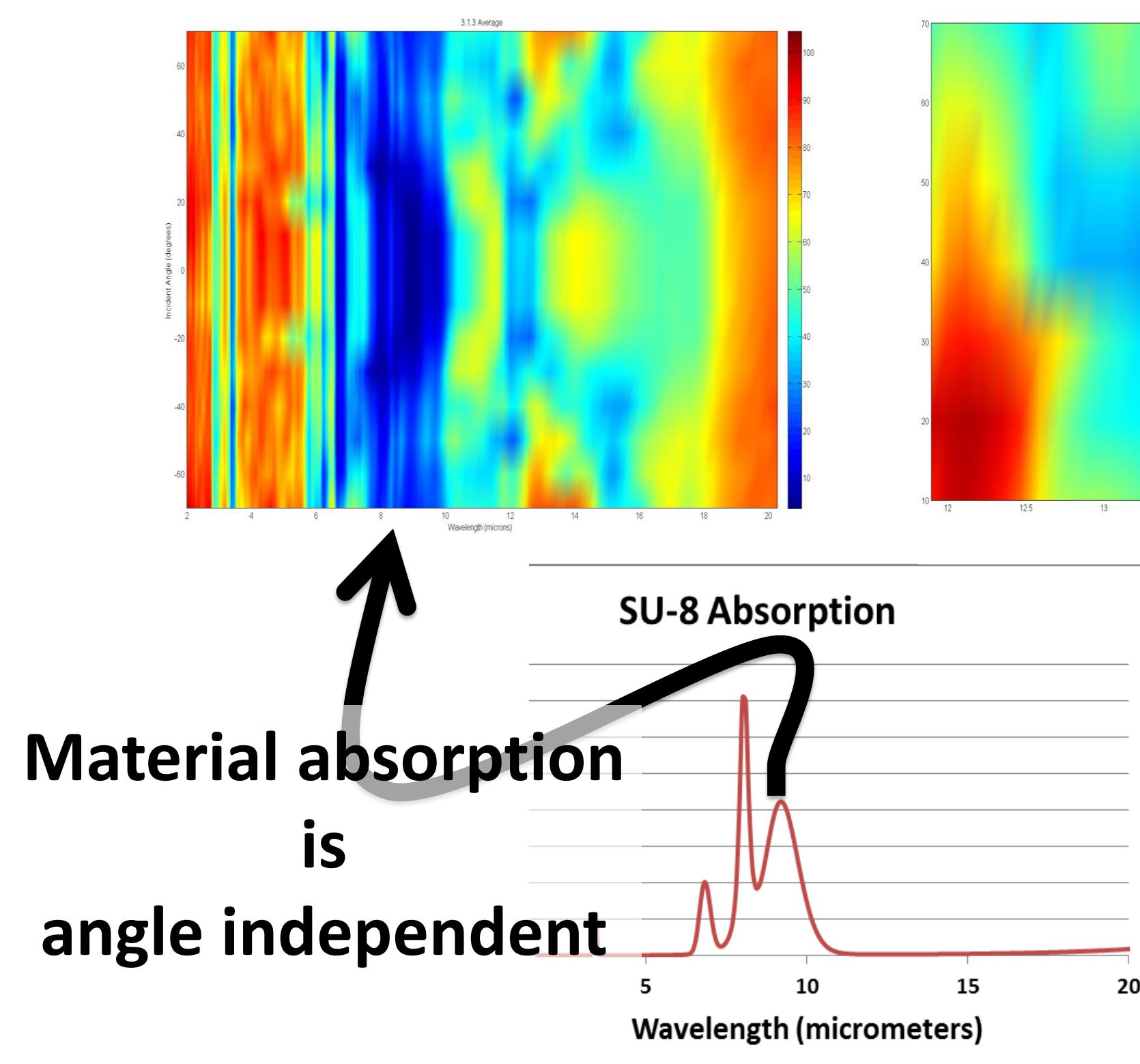
The ability to fabricate 3D micron-scale structures allows us to interact with IR light in new ways

$$1 = R + T + A$$

Kirchoff's Law: Absorption and emission are equivalent, so with $T = 0$ we can use reflectance measurements to find information about emissivity



HDR/FT-IR setup used to measure reflectance of surfaces



Properly designed metallic inclusions allow for the possibility of control over both angular and wavelength dependent Reflectivity/absorption

Angle-dependent reflectance suggests potential to engineer surfaces that emit radiation in a particular direction – a behavior not possible with natural unstructured materials.

Future work: Optimize designs for the metallic inclusions to target specific angle and wavelength combinations specific to application needs.